PATENT ASSIGNMENT

Electronic Version v1.1 Stylesheet Version v1.1

SUBMISSION TYPE:	NEW ASSIGNMENT
NATURE OF CONVEYANCE:	Corrective Recordation regarding transposition of Assignor and Assignee at Reel/Frame: 011523/0078

CONVEYING PARTY DATA

Name	Execution Date
On-Line Technologies, Inc.	01/19/2001

RECEIVING PARTY DATA

Name:	MKS Instruments, Inc.
Street Address:	Six Shattuck Road
City:	Andover
State/Country:	MASSACHUSETTS
Postal Code:	01810

PROPERTY NUMBERS Total: 19

Property Type	Number
Patent Number:	4652755
Patent Number:	4985858
Patent Number:	4824790
Patent Number:	5136154
Patent Number:	5170223
Patent Number:	5196902
Patent Number:	5239488
Patent Number:	5285167
Patent Number:	5349438
Patent Number:	5403433
Patent Number:	5432336
Patent Number:	5440143
Patent Number:	5473429
Patent Number:	5486917

PATENT "REEL: 018231 FRAME: 0804

500150215

Patent Number:	5513828
Patent Number:	5588632
Patent Number:	5604581
Patent Number:	5675412
Patent Number:	5900633

CORRESPONDENCE DATA

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ATTORNEY DOCKET NUMBER:	105690136
NAME OF SUBMITTER:	Michael J. Bevilacqua

Total Attachments: 13

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MB No 0651-0011 (exp. 4/94)				U.S	.DEPARTME: Patent a	NT OF COM nd Trademai	
To the Honorable Commissioner of Patents Name of conveying party(ies): MKS Instruments, Inc. Six Shattuck Road Andover, Massachusetts 01810	(1016	18776 2. Name: Internal z	Name and addr	d original do ess of receiv m-Line Tech	ing party(i	28):	reof.
		Address	8	7 Church Sti	reet		
Assignment	☐ Yes ☐ No	Additional	East Hartford name(s) and addre	Sta ess(es) attached		Zip:	06108
xecution Date: January 19, 2001							,
	nal numbers atta	B. Patent S ached? 🛛	No.(s) ee attached lis Yes No	t			
Name and address of party to whom corresponcerning document should be mailed:	ndence	6. Fotal n	umber of appli	ications and 19	patents inv	olved:	
me: Michael J. Bevilacqua, Esquernal Address: Hale and Dorr LLP 60 State Street	iire		Fee (37 CFR 3 Enclosed Charge fees to	Deposit Ac	count	-	
ty: Boston State: MA	Zip: 02109		additional fees as this application.				count.
			it account num 08-0219 licate copy of this)	by deposit ac	 count.)	
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Statement and signature. To the best of my knowledge and belief, the fo the original document Michael J. Bevilacqua, Esquire	regoing informa	ntion is true	and correct a	nd any attac		a true co _l	
Name of Person Signing	Signature	700	- Cury				
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Commissioner of Patents & Trademarks, Box Assignments

Washington, D.C. 20231

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ale and Dork LLP Docket Number

/21/2001 AAHNED1 00000126 080219 4652755

FC:581 760.00 CH

APPLICATIONS which contain particles sizes, concentration an combustion. It is a bro 4,985,858 (AFR) Method and Apparate APPLICATIONS surface temperature of which does not require stray radiation. It will if fabrication for FUTUR 4,824,790 (AFR) 4/25/89 System and Method for SENSOR — This part FTIR to analyze evolve hydrocarbons so that a semiconductor industry 5,136,154 8/4/92 Method and System for FTIR —An importan It linearizes the detector	This patent covers the methodology for in-situ analysis of hot reactive gas mixtures. The method provides data on gas composition and temperature, as well as particle d temperature. It has been applied to measure coal combustion and black liquor and fundamental patent with application to FUTURE GAS ANALYSIS PRODUCTS. This patent covers a unique method employing the Christiansen dip for measuring the glass, ceramics and other dielectrics. It provides a very accurate, non contact method prior knowledge of the emissivity. It is particularly useful in situations were there is have application for the in-situ measurement of dielectric coatings in semiconductor EPROCESS ANALYSIS PRODUCTS. Thermogravimetric Analysis tent covers a method to couple a thermogravimetric analysis (TGA) apparatus with an add products. It permits an analysis of the tars which are often produced with complete material balance can be obtained. It has application outside the for ANALYTICAL INSTRUMENTATION. Thermogravimetric Detector Signal Correction at patent for all of FTIR-based products using photoconductive detectors such as MCT, as of that the measurements from all instruments are identical. This is essential for that application in CURRENT WAFER AND GAS ANALYSIS PRODUCTS.
APPLICATIONS which contain particles sizes, concentration and combustion. It is a bro 4,985,858 (AFR) Method and Apparate APPLICATIONS surface temperature of which does not require stray radiation. It will fabrication for FUTUR 4,824,790 (AFR) 4/25/89 System and Method for SENSOR — This part FTIR to analyze evolve hydrocarbons so that a semiconductor industry 5,136,154 8/4/92 Method and System for FTIR —An importan It linearizes the detector	This patent covers the methodology for in-situ analysis of hot reactive gas mixtures. The method provides data on gas composition and temperature, as well as particle d temperature. It has been applied to measure coal combustion and black liquor and fundamental patent with application to FUTURE GAS ANALYSIS PRODUCTS . This patent covers a unique method employing the Christiansen dip for measuring the glass, ceramics and other dielectrics. It provides a very accurate, non contact method prior knowledge of the emissivity. It is particularly useful in situations were there is have application for the in-situ measurement of dielectric coatings in semiconductor to the PROCESS ANALYSIS PRODUCTS. Thermogravimetric Analysis tent covers a method to couple a thermogravimetric analysis (TGA) apparatus with an and products. It permits an analysis of the tars which are often produced with complete material balance can be obtained. It has application outside the for ANALYTICAL INSTRUMENTATION . The Photoconductive Detector Signal Correction to patent for all of FTIR-based products using photoconductive detectors such as MCT. The so that the measurements from all instruments are identical. This is essential for that application in CURRENT WAFER AND GAS ANALYSIS PRODUCTS .
(AFR) APPLICATIONS surface temperature of which does not require stray radiation. It will if fabrication for FUTUR 4,824,790 (AFR) 4/25/89 System and Method for SENSOR - This par FTIR to analyze evolve hydrocarbons so that a semiconductor industry 5,136,154 8/4/92 Method and System for FTIR -An importan It linearizes the detector	This patent covers a unique method employing the Christiansen dip for measuring the glass, ceramics and other dielectrics. It provides a very accurate, non contact method prior knowledge of the emissivity. It is particularly useful in situations were there is have application for the in-situ measurement of dielectric coatings in semiconductor the PROCESS ANALYSIS PRODUCTS. For Thermogravimetric Analysis tent covers a method to couple a thermogravimetric analysis (TGA) apparatus with an ed products. It permits an analysis of the tars which are often produced with complete material balance can be obtained. It has application outside the for ANALYTICAL INSTRUMENTATION. For Photoconductive Detector Signal Correction to patent for all of FTIR-based products using photoconductive detectors such as MCT. It is so that the measurements from all instruments are identical. This is essential for that application in CURRENT WAFER AND GAS ANALYSIS PRODUCTS.
(AFR) SENSOR – This pail FTIR to analyze evolve hydrocarbons so that a semiconductor industry 5,136,154 8/4/92 Method and System for FTIR – An important It linearizes the detector	tent covers a method to couple a thermogravimetric analysis (TGA) apparatus with an old products. It permits an analysis of the tars which are often produced with complete material balance can be obtained. It has application outside the for ANALYTICAL INSTRUMENTATION. Or Photoconductive Detector Signal Correction at patent for all of FTIR-based products using photoconductive detectors such as MCT. It is so that the measurements from all instruments are identical. This is essential for the has application in CURRENT WAFER AND GAS ANALYSIS PRODUCTS.
FTIR —An importan It linearizes the detector	t patent for all of FTIR-based products using photoconductive detectors such as MCT. It is so that the measurements from all instruments are identical. This is essential for the has application in CURRENT WAFER AND GAS ANALYSIS PRODUCTS.
	Divergent Radiation as in Spectroscopy and Instrument and Method Utilizing
5,170,223 12/8/92 Same SENSOR – This pat	ent allows the Bomem FTIR or an FTIR with a similar interferometer to operate nission and transmission mode.
Two-Beam Interferom Same	eter Apparatus and Method, and Spectrometer and Instrument Utilizing the
5,239,488 8/24/93 Apparatus and Method and Radiance Measure SENSOR – This pate	d for Determining High Temperature Surface Emissivity Through Reflectance
5,285,167 2/8/94 <u>FTIR-</u> This patent co	s for Signal Compression vers methods for improving the dynamic range of the A to D converter in the FTIR sently used in our products.
5,349,438 9/20/94 <u>FTIR</u> – This patent c translational and rotation	mic Support of a Reflective Element and Interferometer Comprising the Same overs On-Line's unique mirror translation system, which provides isolation from nal vibrations and the cross spring pivot structure used to construct the device. It is CURRENT AND FUTURE METROLOGY AND GAS PRODUCTS.
5,403,433 4/4/95 <u>ALGORITHMS</u> _T	s for Monitoring Layer Processing This is a fundamental patent covering methods of analysis for surface layer thickness ature. It is used in Tool ++ for CURRENT AND FUTURE METROLOGY
5,432,336 7/11/95 FTIR- This is an imp	tion Method and System provement in the method of patent US 5,136,154. It is employed in all FTIR-based URE METROLOGY AND GAS PRODUCTS.
	nalysis Gas Cell at covers the 20/20 Multi-Pass Gas Cell. The unique design allows a higher optical cell than the standard White Cell. It is applied in the INDUCT and MULTI-GAS
Method and Apparatus	for Controlling the Reciprocating Translation of an Interferometer Reflector or

5,473,429	12/5/95	Other Body FTIR – This patent covers the fast mirror motion turn around circuitry. It is used in all FTIR-based CURRENT AND FUTURE METROLOGY AND GAS PRODUCTS.
5,486,917	1/23/96	Flexture Plate Motion-Transfer Mechanism, Beam-Splitter Assembly, and Interferometer Incorporating the Same FTIR – This patent covers many of the unique design features of On-Line's FTIR. It is used in all FTIR-based CURRENT AND FUTURE METROLOGY AND GAS PRODUCTS.
5,513,828	5/7/96	Vibration Immunizing Dynamic Support Structure FTIR – This patent covers the vibration isolating mirror motion system. It is used in all FTIR-based CURRENT AND FUTURE METROLOGY AND GAS PRODUCTS.
5,588,632	12/31/96	Dynamic Support Structure FTIR - This patent covers an early prototype.
5,604,581	2/18/97	Film Thickness and Free Carrier Concentration Analysis Method and Apparatus ALGORITHM – This patent covers the method for analyzing multi-layer structures to determine the thickness and composition. It is used in TOOL ++, EPI ON LINE and EPISCAN.
5,675,412	10/7/97	System Including Unified Beamsplitter and Parallel Reflecting Element, And Retroreflecting Component FTIR – This patent covers the very rugged interferometer design used in On-Line's 2100 FTIR. It is used in all FTIR-based CURRENT AND FUTURE METROLOGY AND GAS PRODUCTS.
5,900,633	5/4/99	Spectrometric Method for Analysis of Film Thickness and Composition on a Patterned Sample <u>ALGORITHM</u> — A method for analyzing films deposited on top of patterns. It will be the basis for INTEGRATED METROLOGY PRODUCTS.

PATENT

INTELLECTUAL PROPERTY SECURITY AGREEMENT

This Intellectual Property Security Agreement is entered into as of January 19, 2001 between MKS Instruments, Inc. ("Lender") and On-Line Technologies, Inc. ("Grantor").

RECITALS

Lender has agreed to make certain advances of money and to extend certain financial accommodations to Grantor (the "Loans") in the amounts and manner set forth in that certain Loan and Security Agreement between Lender and Grantor dated of even date herewith (as the same may be amended, modified or supplemented from time to time, the "Loan Agreement"). Lender is willing to make the Loans to Grantor, but only upon the condition, among others, that Grantor shall grant to Lender a security interest in, among other things, certain Copyrights, Trademarks and Patents to secure the obligations of Grantor under the Loan Agreement. Capitalized terms not otherwise defined herein shall have the meanings ascribed to them in the Loan Agreement.

Pursuant to the terms of the Loan Agreement, Grantor has granted to Lender a security interest in all of Grantor's right, title and interest, whether presently existing or hereafter acquired, in, to and under all of the Collateral.

NOW, THEREFORE, for good and valuable consideration, receipt and sufficiency of which is hereby acknowledged, and intending to be legally bound, as collateral security for the prompt and complete payment when due of its obligations under the Loan Agreement, Grantor hereby represents, warrants, covenants and agrees as follows:

AGREEMENT

To secure its obligations under the Loan Agreement, subject to all prior security interests of record, Grantor grants and pledges to Lender a security interest in all of Grantor's right, title and interest in, to and under its Intellectual Property Collateral (including without limitation those Copyrights, Patents and Trademarks listed on Schedules A, B and C hereto), together with all goodwill of the business symbolized by the Trademarks, the right to sue for past, present and future infringements, all rights corresponding thereto throughout the world and all re-issues, divisions, continuations, renewals, extensions and continuations-in-part thereof, and all proceeds of each of the foregoing (including, without limitation, all license royalties and proceeds of infringement suits).

This security interest is granted in conjunction with the security interest granted to Lender under the Loan Agreement. The rights and remedies of Lender with respect to the security interest granted hereby are in addition to those set forth in the Loan Agreement and the other Loan Documents, and those which are now or hereafter available to Lender as a matter of law or equity. Each right, power and remedy of Lender provided herein or in the Loan Agreement or any of the Loan Documents, or now or hereafter existing at law or in equity shall be cumulative and concurrent and shall be in addition to every right, power or remedy provided for herein and the exercise by Lender of any one or more of the rights, powers or remedies

provided for in this Intellectual Property Security Agreement, the Loan Agreement or any of the other Loan Documents, or now or hereafter existing at law or in equity, shall not preclude the simultaneous or later exercise by any person, including Lender, of any or all other rights, powers or remedies.

IN WITNESS WHEREOF, the parties have cause this Intellectual Property Security Agreement to be duly executed by its officers thereunto duly authorized as of the first date written above.

GRANTOR:

ON-LINE TECHNOLOGIES, INC.

Address of Grantor:

87 Church Street
East Hartford, CT 06108

Name: Peter R. Solomon
Title: President

LENDER:

Address of Lender:

MKS INSTRUMENTS, INC.

Six Shattuck Road
Andover, MA 01810

Name: Ronald C. Weigner
Title: Vice President & Chief Financial Officer

provided for in this Intellectual Property Security Agreement, the Loan Agreement or any of the other Loan Documents, or now or hereafter existing at law or in equity, shall not preclude the simultaneous or later exercise by any person, including Lender, of any or all other rights, powers or remedies.

IN WITNESS WHEREOF, the parties have cause this Intellectual Property Security Agreement to be duly executed by its officers thereunto duly authorized as of the first date written above.

GRANTOR:

ON-LINE TECHNOLOGIES, INC.

Address of Grantor:

87 Church Street

East Hartford, CT 06108

Title: President

LENDER:

Address of Lender:

Six Shattuck Road Andover, MA 01810 MKS INSTRUMENTS, INC

Name: Ronald C. Weigner

Title: Vice President & Chief Financial Officer

STATE OF CONNECTICUT COUNTY OF HARTEORD

The foregoing instrument was acknowledged this 26th day of January, 2001 by Peter R. Solomon, the President of On-Line Technologies, Inc. (the "<u>Grantor</u>"), to be his free act and deed in said capacity and the free act and deed of the Grantor, on behalf of said Grantor, before me,

Notary Public COMMISSIONER OF THE SUPERIOR CONRT

COMMONWEALTH OF MASSACHUSETTS COUNTY OF SUFFOLK

The foregoing instrument was acknowledged this 26th day of January, 2001 by Ronald C. Weigner, the Vice President and Chief Financial Officer of MKS Instruments, Inc. (the "Lender"), to be his free act and deed in said capacity and the free act and deed of the Lender, on behalf of said Lender, before me,

Notary Public My commission expires:

STATE OF CONNECTICUT	
COUNTY OF	

The foregoing instrument was acknowledged this 26th day of January, 2001 by Peter R. Solomon, the President of On-Line Technologies, Inc. (the "Grantor"), to be his free act and deed in said capacity and the free act and deed of the Grantor, on behalf of said Grantor, before me,

> **Notary Public** My commission expires:

COMMONWEALTH OF MASSACHUSETTS COUNTY OF SUFFOLK

The foregoing instrument was acknowledged this 26th day of January, 2001 by Ronald C. Weigner, the Vice President and Chief Financial Officer of MKS Instruments, Inc. (the "Lender"), to be his free act and deed in said capacity and the free act and deed of the Lender, on behalf of said Lender, before me,

Notary Public Many! Low My commission expires: 4/15/01

SCHEDULE A

Copyrights

Description

Registration/
Application Number

Registration/ Application Date

PATENT

SCHEDULE B

Patents

<u>Description</u>

Registration/
Application Number

Registration/ Application Date

PATENT

SCHEDULE C

Trademarks

Description

Registration/
Application Number

Registration/
Application Date

PATENT REEL: 018231 FRAME: 0816

RECORDED: 09/12/2006